

<b>Form PTO-1449</b>  <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>  <b>INFORMATION DISCLOSURE STATEMENT</b> <b>BY APPLICANT</b>  (Use several sheets if necessary)	<b>ATTY. DKT. NO.</b> 566.38683CX1	<b>SERIAL NO.</b> Not yet assigned
	<b>APPLICANT</b> Yoshida et al	
	<b>FILING DATE</b> Herewith	<b>GROUP</b> 3723 (anticipated)

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## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						

## FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
SLU	AM	JP 8-134435	May 1996	Japan			
	AN	JP 1-266183	Oct. 1989	Japan			
SLM	AO	JP 781932	1995	Japan			x
	AP						
	AQ						
	AR						
	AS						
	AT						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SLM	AU	"The Rietveld Method", Oxford University Press (1993)					
	AV	"McGraw-Hill Dictionary of Scientific and Technical Terms (5 <sup>th</sup> Ed.) (1994) p. 388.					
	AW	"Particle Size Distributions from Angular Variation of Intensity of Forward-Scattered Light at Very Small Angles" J. Chem. Phys., vol 59, pp 841 - 844 (1955).					
SLM	AX	"The Determination of Pore Volume and Area Distribution in Porous Substances. I. Computations from Nitrogen Isotherms" J. Am. Chem. Soc., Vol 73, pp. 373-380 (1951).					
	AY						
	AZ						
<b>Examiner</b> Srawles McDonald				<b>Date Considered</b> 10/23/03			